

Search Notes

Application/Control No.

10/630,347

Examiner

Tai T. Nguyen

Applicant(s)/Patent under
Reexamination

INLOW, MARK C.

Art Unit

2612

SEARCHED

Class	Subclass	Date	Examiner
340	654 686.1 686.4 687	10/1/2007	TN
702	34 187	10/1/2007	TN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
SEARCH AS ABOVE		10/1/2007	TN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR